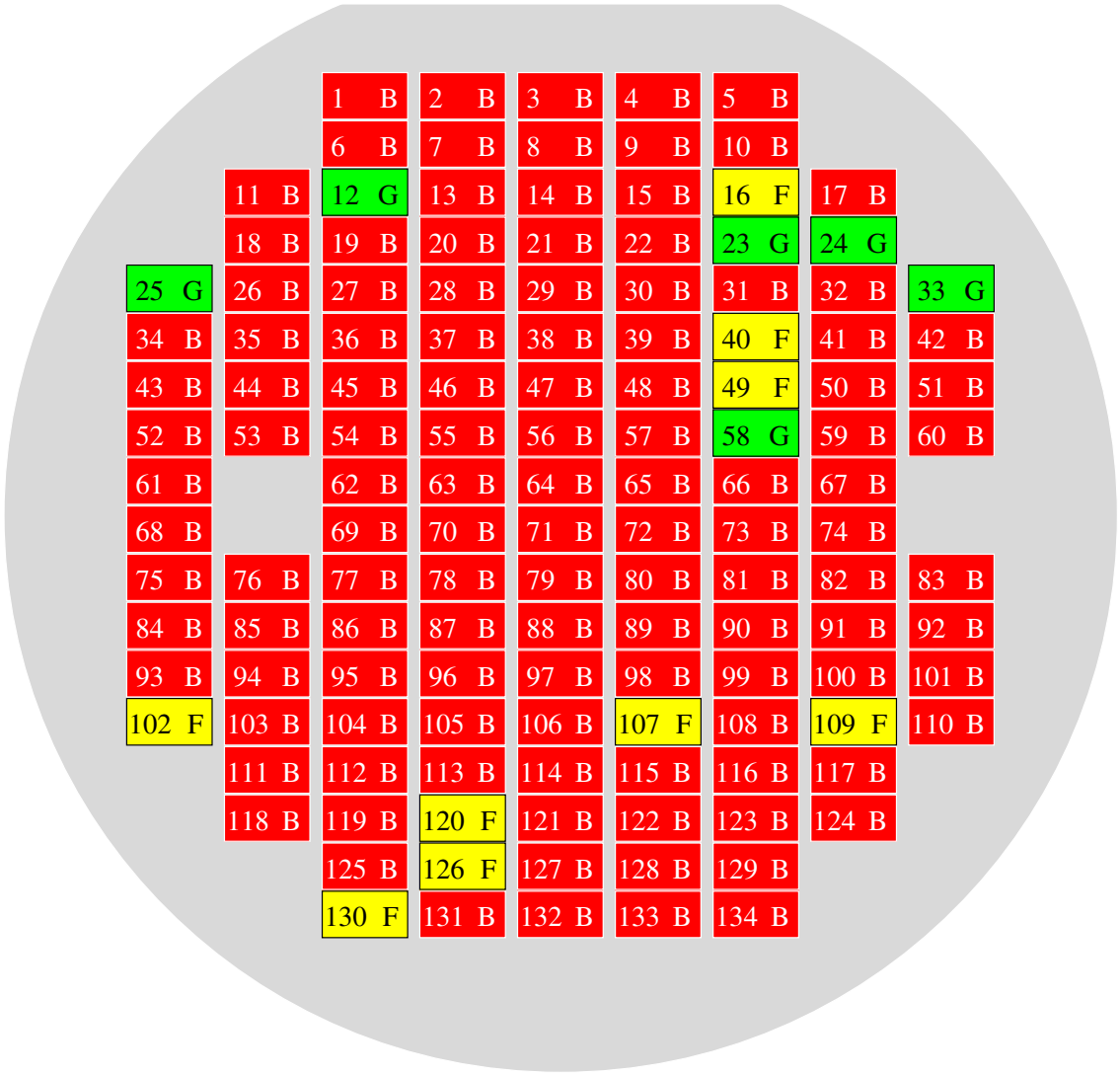
Die quality map for wafer 230 s/n: 21316-13-20

Date: 10/28/99



# B	Bad die
# F	Fair die
# G	Good die
# N	No info
# *	Manually tagged